

Title: Quantum Error Correction 8A

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Abstract: Assumptions for fault tolerance, extended rectangles, good, bad, and correct rectangles.

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"Gate errors":

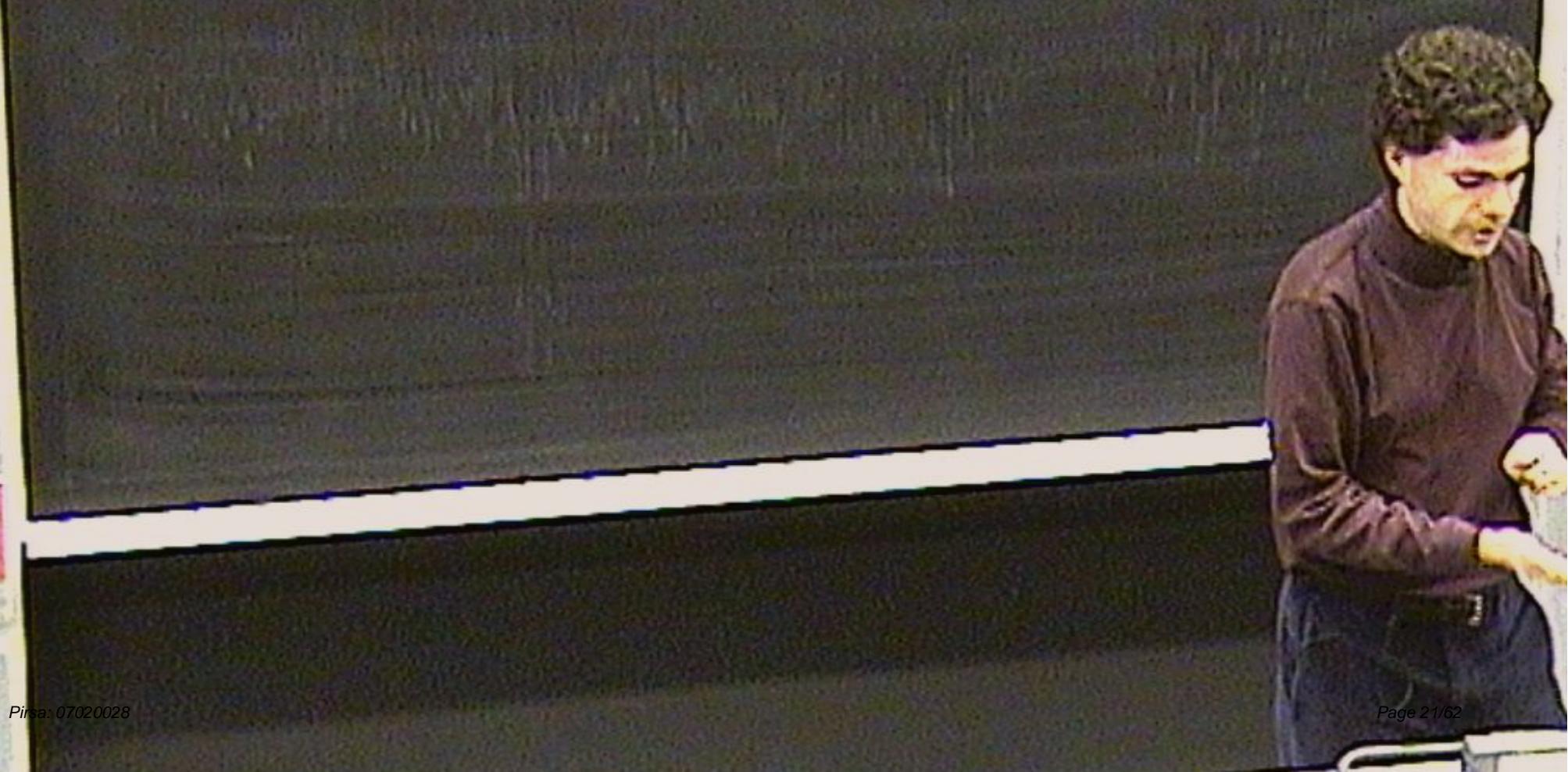


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Each location in the original circuit corresponds to an Extended Rectangle, consisting of the corresponding FT gadget plus the EC steps before & after it. ($\text{exRec} = \text{"extended rectangle"}$)

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Def: An exRec (truncated or not) is good if it contains at most τ faulty locations. An exRec is bad if it contains more than τ faults.

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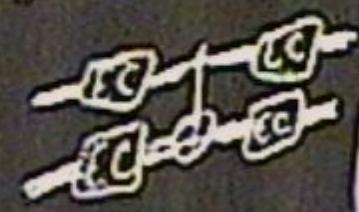


The EC steps between rows

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CNOT eRec : 

Preparation eRec:

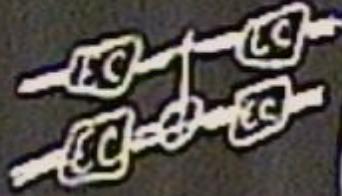
The EC steps before error

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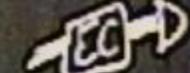
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Preparation eRec:



Measurement eRec:



Theorem: $[Good \Rightarrow Correct]$:

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$$\text{Good} = \text{Ideal}$$

Thm. [Good \Rightarrow Correct]: For a good exRec,

$$\begin{aligned} -\text{Ed} \circ \text{Ec} \triangleright &= -\text{Ec} \triangleright \circ \text{D}^{\text{ideal}} \\ (-\text{Ec} \triangleright) &= \text{D}^{\text{ideal}} \\ -\text{Ec} \triangleright &= -\text{Ec} \triangleright \text{D}^{\text{ideal}} \end{aligned} \quad \left. \begin{array}{l} \\ \\ \end{array} \right\} \text{"correctness"}$$

Thm. [Good \Rightarrow Correct]: For a good exRec,

- $\overrightarrow{E_0 \circ E_1 \circ E_2} = \overrightarrow{E_0 \circ E_1}$
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} "correctness"

Proof:

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Proof: $\begin{array}{c} \textcircled{F} \\ (-\boxed{Ec} \circ \textcircled{O} \circ \boxed{Ec} \rightarrow (Ec)) \circ \textcircled{F} \end{array}$



Thm: [Good \Rightarrow Correct]: For a good exRec,

$$\begin{aligned} \neg \text{EC} \circ \text{O} \circ \text{EC} \triangleright &= \neg \text{EC} \triangleright \circ \text{O}_{\text{ideal}} \\ \neg \text{EC} \triangleright &= \text{O}_{\text{ideal}} \\ \neg \text{EC} \triangleright &= \neg \text{EC} \triangleright \circ \text{D}^{\text{ideal}} \end{aligned} \quad \left. \begin{array}{l} \text{ideal} \\ \text{ideal} \end{array} \right\} \text{"correctness"}$$

Proof: $\neg \text{EC} \circ \text{O} \circ \text{EC} \triangleright \stackrel{(\text{EC})}{=} \neg \text{EC} \circ \text{O} \circ \text{EC} \triangleright$
 (r_1, r_2, r_3)
 $(\text{get } r) \neg \text{EC} \circ \text{O} \circ \text{EC} \triangleright =$

Thm. [Good \Rightarrow Correct]: For a good exec,

$$\begin{aligned} \neg(\mathbf{E}C \rightarrow D) &= \neg(\mathbf{E}C \rightarrow \neg D) \\ \neg(\mathbf{E}C \rightarrow) &= \neg C \\ \neg(\mathbf{E}C \rightarrow D) &= \neg C \rightarrow \neg D \end{aligned} \quad \left. \begin{array}{c} \text{ideal} \\ \text{ideal} \end{array} \right\} \text{"correctness"}$$

Proof : $\neg \text{EC} \rightarrow \text{EC} \rightarrow (\text{EC}) \neg \text{EC} \rightarrow \text{EC} \rightarrow \dots$
 $(\text{EC}_1, \text{EC}_2, \text{EC}_3, \dots)$

on the same qubit at the same time

(Gate 1 Reg)



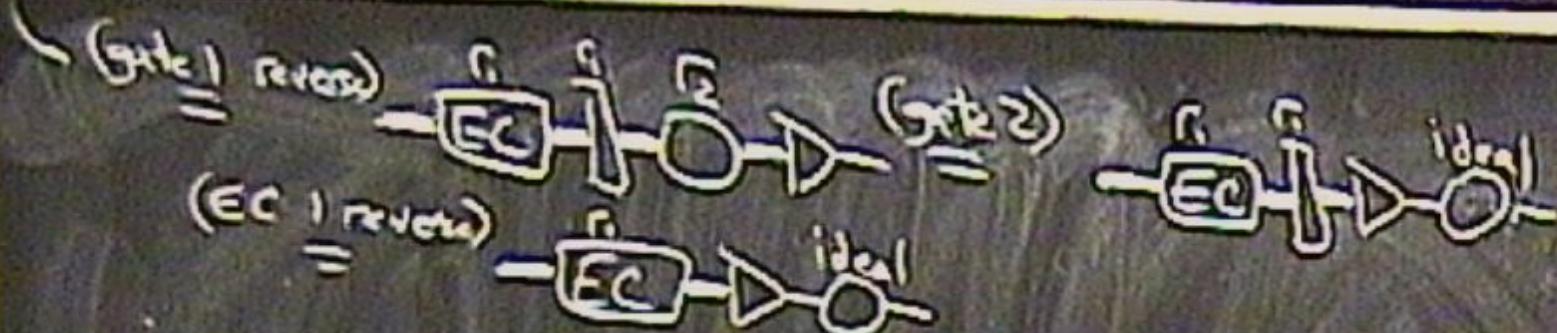
(Gate 2)







Corollary: For a truncated expr,



Corollary: For a truncated exec, good \Rightarrow correct.

Proof: Insert EC steps w/ no errors to replace truncated ones.